

Application/Con	trol	No.	

09/766,558

MOTIWALA ET AL.

Applicant(s)/Patent under Reexamination

Art Unit

Examiner
Ted M. Wang

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SEARCHED			
Class	Subclass	Date	Examiner
375	140, 326	12/21/2007	TW
375	142, 143	12/21/2007	TW
375	150, 152	12/21/2007	TW
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
375	140, 326	12/21/2007	TW
375	142/143	12/21/2007	TW
375	150, 152	12/21/2007	TW

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST - USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB, see attached search report	12/21/2007	TW
ODP - searched and reviewed	12/21/2007	τw
Inventor search - ((Quaeed with Motiwala) or (Christopher with Riddle) or (Luca with Blessent) or ("Shih-Yi" with Yeh) or (Ro	12/21/2007	T.W
IEEE advance search - (partition* or division or divid* or separat* or pars* or break* or broke*) an frame and portion	12/21/2007	TW
IEEE author's search - Motiwala Q. or Riddle C. or Blessent L. or Yeh S. Y.	12/21/2007	TW